

NCITS B10.6 Meeting Minutes
West Palm Beach, Florida
Wednesday, January 19, 2005
8:00 A.M. Local Time

1) Call to Order (Chair Arthur Bobrow)

Arthur B called the meeting to order at 8:05am

2) Attendees introduction - Roll Call

1. Arthur Bobrow (chair)	H. W. Sands
2. Terry Schindler (secretary)	Brush / Q-Card
3. Denny Warwick	DataCard
4. Brad Paulson	Plastag Corporation
5. Joe Naujokas	Naujokas & Associates/ICMA
6. Kevin Tall	Eclipse Laboratories
7. Steve Schwartz	Kurz Transfer Products
8. Trent Argyle	Oberthur Card Systems
9. Simmon Shepherd	Dupont Teijin Films
10. Derek Page	AXALTO
11. Guy Meeker	Colorado Plasticard
12. John Ko	3M
13. Shannon Crawford-Taylor	CFC International
14. Simon Shepherd	Dupont Teijen Films
15. Traci Johnson	Fargo Electronics
16. Josh Nippolot	Fargo Electronics
17. Ed Gesham	Giesecke & Deviiient Inc.
18. Dan Persico	H. W. Sands
19. Julie Hermanson	Plastag Corporation
20. William Crawford	Waytek Corporation

3) Mailing List Review (Secretary Terry Schindler)

The mailing list was circulated.

Arthur B. announced we would start to send warning notice around to individuals that miss 3 meeting in a row to inform loss of voting rights.

4) B10.6 Membership Review, Voting Qualifications

Arthur B. compiled a spreadsheet with attendance recorded for the last three meetings. Arthur will send out some jeopardy letters before our next meeting.

5) Review INCITS Antitrust statement (Document B10.6-2004-34)

Members present agree with the anti-trust guidelines.

6) Review the B10.6 Agenda and discuss changes or additional topics for other business

Joe N. requested a discussion about how to measure raised surfaces.

Steve S. requested an update about the ceramic test head issue.

7) Review Minutes: Boston B10.6 Meeting B10.6-2004-40

The minutes were accepted without comments.

8) General discussion Minutes from Sydney, ISO/IEC/SC17 WG-1 Meetings:

a) WG-1 General Meeting, David May, Convener, B10.6-2005-2

Terry S. reviewed the highlights in the minutes from the last WG1 meeting.

Brad P. 1st

Denny W. second

**9) B10.6-2005-10 FCD ISO/IEC 10373-1 Identification cards - Test methods - Part 1:
General characteristics.**

a) (B10.6-2005-2) Minutes from Sydney Section 2.6

Denny W. requested that we add a reminder in the US position about the following

Note: If motorized equipment is used to scan the card, the distance between individual measurement positions should be less than or equal to half the diameter of the aperture. For a continuous scanning method, the speed should be less than 0,05 times the aperture diameter divided by the response time of the LED/detector system.

Guy M. gave the motion to include the above in the US position.

Derek P. gave a second motion

Joe N. discussed the card thickness measurement from clause 5.2.1, which describes taking one measurement in each of 4 quadrants in unraised areas. Joe received email indicating some confusion related to this in Germany and in China.

5.2.1 Thickness of card measurements

5.2.1.1 Apparatus

A micrometer with a flat anvil and spindle whose diameter is within the range of 3 mm to 8 mm (0.12 in to 0.32 in), having a precision of 0,005 mm (0.00020 in).

5.2.1.2 Procedure

Pre-condition the sample card according to 4.2 before testing and conduct the test under the test environment defined in 4.1. Use the micrometer to measure the thickness of the card at four points, one in each of the four quadrants of the card (see Figure 2 for the location of the quadrants). The measurements shall be made at locations on the card that do not include signature panels, magnetic stripes or contacts (integrated circuit/s cards), or any other raised area.

The micrometer force shall be 3,5 N to 5,9 N (0.79 lbf to 1.33 lbf).

5.2.1.3 Test report

The test report shall give the maximum and the minimum values of the four measurements.

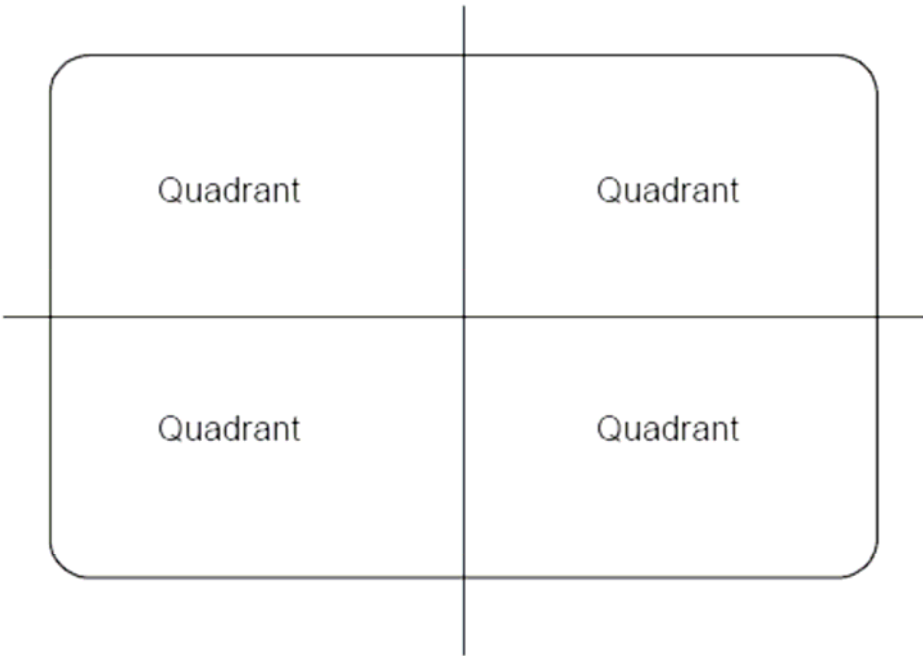


Figure 2 - Assignment of quadrants

Kevin T. pointed out that the term thickness is misleading in 8.13 of 7810

8.13 Surface distortions

Raised areas shall not increase the overall card thickness by more than 0,10 mm (0.004 in) except for embossed characters as defined in ISO/IEC 7811-1.

Joe N. recommended changes for 10373-1 to the title of clause 5.14 Embossing relief height of characters to include a test method for all raised areas.

Denny W. recalled a discussion from past meetings where we need to prevent cards from having raised areas on both sides. Height measurements from an adjacent surface to a raised area must take total thickness of raised area on both sides into account.

Surface distortion test method for magnetic stripes is the preferred method for measuring raised areas. Denny W. suggested a US position to add to 10373-1 a test method 5.1x SURFACE DISTORTIONS and RAISED AREAS.

Surface distortions and raised areas shall be measured with apparatus and procedures used for surface profile of the magnetic stripe in 10373-2.

10) B10.6-2005-7 FCD ISO/IEC 10373-2

Identification cards – Test methods – Part 2: Cards With Magnetic Stripes.

a) B10.6-2005-2 Minutes from Sydney Section 2.7

Terry S. reviewed the highlights of the minutes.

Steve S. asked if ceramic heads could be discussed at this time.

Denny W. reviewed a new draft of FCD 10373-2 and pointed out a note located above figure 12 that WG1 agreed to pull out at the meeting in Sydney.

NOTE - Discrepancies in signal amplitude results have been observed when wear resistant coatings have been used. It is admissible to use heads with wear resistant coatings for quality control purposes only (see Annex A).

Terry S. explained the note is confusing because quality control is used. Within ISO we could not find a common definition for the term quality control. At least two countries use the term quality control on the same level as determining ISO compliance. Terry S. is convinced that the term quality control should not be used even in a note.

FCD 10373-2 will not be discussed at the Barcelona WG1 meeting. There will be time to review FCD 10373-2 at the August B10.6 meeting before the vote is due. B10.6 can add comments at that time.

b) B10.6-2005-11 PTB contribution magnetic stripe wear

Denny W. recalled that the new test method for magnetic stripe wear would be discussed as a part of card durability test methods.

11) Review B10.6-2004-32 WD8484_2. Magnetic stripes on savings books

a) B10.6-2004-44 1N1368 ISO8484 passbook media

No comments on this contribution were offered.

b) B10.6-2004-46 Magnetic stripe thickness measurements

Shannon CT reviewed the stripe thickness measurements. The measurements will be included in the US position without comments.

c) B10.6-2005-8 Magnetic stripe signal measurements

Terry S. reviewed the magnetic stripe signal measurements. B10.6 decided to include the measurements into the US position for review at WG1 without comments.

d) B10.6-2005-12 Passbook measurements contribution

Denny W. reviewed the document. Denny asked Kevin T. to recalculate the magnetic stripe surface distortion measurements. The surface measurements will be included into the US position without comments.

12) New Work Proposal 600 Oe magnetic stripe 7811-8

a) B10.6-2005-1 WP 7811-8 contribution

Title: ISO/IEC 7911: Identification Cards - Recording Techniques – Part 8: 650 Oersted Magnetic Stripes,

Relevant documents to be considered - ISO/IEC 10373-2 , ISO/IEC 10373-2

b) NP Ballot – ISO/IEC 7811-8 – Identification cards – Recording Technique – Part 8: 650 Oersted Magnetic Stripes SC/JTC 1 Due Date: 03/13/2005

Joe N. reviewed the ballot and some minor corrections were offered.

Terry S. received 600 Oe card samples from Joe N. Terry will test the cards and provide additional data for discussion at Barcelona WG1 meeting.

13) Discussion new WG1 work proposal for limited use PICC

a) b10.6-2005-3 AFNOR 15457 with PICC

B10.6 will request NCITS to issue a call for experts related to physical characteristics of thin flexible proximity integrated circuit cards. We need some experts in the field of ticket dispensing equipment and we need experts in the field of thin flexible card production or ticket production.

14) Other Business:

No other business.

15) Review US position for the WG1 meeting in Barcelona

Denny W. reviewed the US position. The US position was accepted without further comments.

First motion Derek P.

Second motion Steve S.

16) Call for attendance of the WG1 meeting in Barcelona volunteer for HOD

Terry S. accepted the Head of Delegation responsibility at WG1 Barcelona.

Attendance to WG1

Denny Warwick

Joe Naujokas

Terry Schindler

Sud Deland

17) Next B10.6 Meetings:

- a) May 4, 2005 Discover Financial Services/CFC – Chicago Northbrook, Ill
- b) September 14, 2005 Freeport, MN / Jim Russell

18) Call for motions to close the meeting

Brad P 1st

Denny W. 2nd

19) Salutation

The minutes were respectfully written and submitted by Terry Schindler.